





























Exams for group S13-403

Fri, 22 Dec	09:00 — 12:00	TEST	Scientific Research Work  Shagurin I.I.  dep.27
Fri, 22 Dec	12:00 — 15:00	ATT	Software Support of Modern Microprocessors and Microcontrollers  Shagurin I.I.  D-311
Mon, 25 Dec	09:00 — 12:00	TEST	Microelectronic Radio Devices  Bocharov Y.I.  D-311
Mon, 25 Dec	12:00 — 15:00	ATT	Sensors Based on Micro- and Nanotechnologies  Podlepetskiy B.I.  D-311
Mon, 25 Dec	15:00 — 18:00	TEST	Quantum Radiophysics  Larkin A.I.  K-1117
Tue, 26 Dec	09:00 — 12:00	TEST	Information Measurement Systems  Belyakov V.V.  D-303
Tue, 26 Dec	12:00 — 15:00	ATT	Reliability and Radiation Resistance of Integrated Circuits  Zebrev G.I.  D-303
Tue, 26 Dec	15:00 — 18:00	TEST	Management and Marketing  Silenko A.N.  B-100
Thu, 28 Dec	09:00 — 12:00	ATT	Principles of Optoelectronics  Voronov Y.A.  D-311
Thu, 28 Dec	12:00 — 15:00	TEST	Life Safety  Hayretdinov S.I.  E-214
Wed, 10 Jan	09:00 — 13:00	EXAM	Software Support of Modern Microprocessors and Microcontrollers  Shagurin I.I.  D-303
Mon, 15 Jan	09:00 — 13:00	EXAM	Principles of Optoelectronics  Voronov Y.A.  D-311
Fri, 19 Jan	09:00 — 13:00	EXAM	Reliability and Radiation Resistance of Integrated Circuits  Zebrev G.I.  D-303
Wed, 24 Jan	09:00 — 13:00	EXAM	Sensors Based on Micro- and Nanotechnologies  Podlepetskiy B.I.  D-405